

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

1284-01

SERIAL NO.

09/914,515

APPLICANT Rainer Heintzmann et al.

FILING DATE

August 29, 2001

GROUP

LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

EXAMINER INITIAL*		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SY	AA	5	6	8	7	6	0	4	02/02/99	Meir Ben-Levy et al.			
	AB												
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	AF												
	AG												
	AH												
	AI												
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
SY	AL	WO 98/45745	10/15/98	PTO			x	
	AM							
	AN							
	AO							
	AP							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

SY	AR	David R. Sandison et al., <u>QUANTITATIVE FLUORESCENCE CONFOCAL LASER SCANNING MICROSCOPY (CLSM)</u> , James B. Pawley, editor, Handbook of Biological Confocal Microscopy, Chapter 3:47-50, 1995
		Ernst H.K. Stelzer et al., <u>FUNDAMENTAL REDUCTION OF THE OBSERVATION VOLUME IN FAR-FIELD LIGHT MICROSCOPY BY DETECTION ORTHOGONAL TO THE ILLUMINATION AXIS: CONFOCAL THETA MICROSCOPY</u> , Optics Communications, 111:536-547, 1994
SY	AS	Roger Y. Tsien et al., <u>FLUOROPHORES FOR CONFOCAL MICROSCOPY: PHOTOPHYSICS AND PHOTOCHEMISTRY</u> , James B. Pawley, editor, Handbook of Biological Confocal Microscopy, Chapter 16:267-268, 1995
		T. Wilson et al., <u>A NEW APPROACH TO THREE DIMENSIONAL IMAGING IN MICROSCOPY</u> , Cell Vision, Vol. 4, No. 2, 231, March 1997
SY	AT	T. Wilson et al., <u>AN APERTURE CORRELATION APPROACH TO CONFOCAL MICROSCOPY</u> , Proceedings of SPIE, Vol. 2984:21-23, 1997
		Robert Windecker et al., <u>THREE-DIMENSIONAL TOPOMETRY WITH STEREO MICROSCOPES</u> , Optical Engineering, 36(12):3372-3377, December 1997

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*[Signature]*DATE CONSIDERED *1/16/03*

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SY	AA	4	5	2	5	8	5	8	06/25/85	Harvey E. Cline et al.			
SY	AB	4	6	2	1	9	1	1	11/11/86	Frederick Lanni et al.			
SY	AC	4	6	3	1	5	8	1	12/23/86	Kjell S. Carlsson			
SY	AD	4	9	2	9	9	5	1	05/29/90	James G. Small			
SY	AE	5	0	3	4	6	1	3	07/23/91	Winfried Denk et al.			
SY	AF	5	6	7	1	0	8	5	09/23/97	Mats G.L. Gustafsson et al.			
SY	AG	5	7	3	1	5	8	8	03/24/98	Stefan Hell et al.			
SY	AH	5	7	7	7	7	3	2	07/07/98	Pekka Hanninen et al.			
SY	AI	5	7	9	6	1	1	2	08/18/98	Koji Ichie			
SY	AJ	5	8	0	1	8	8	1	09/01/98	Frederick Lanni et al.			
SY	AK	5	8	2	8	4	5	9	10/27/98	Yaron Silberberg			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
SY	AL	EP 0 491 289 A1	06/24/92	Europe			x	
SY	AM	DE 43 26 473 A1	02/09/95	Germany			Abstract only	
SY	AN	WO 97/06509	02/20/97	PTO			x	
SY	AO	WO 97/11355	03/27/97	PTO			x	
SY	AP	WO 97/31282	08/28/97	PTO			x	

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SY	AR	Mats G.L. Gustafsson et al., <u>3D WIDEFIELD MICROSCOPY WITH TWO OBJECTIVE LENSES: EXPERIMENTAL VERIFICATION OF IMPROVED AXIAL RESOLUTION</u> , Proceedings of SPIE, 2655:62-66, 1996
		R. Heintzmann et al., <u>LATERALLY MODULATED EXCITATION MICROSCOPY: IMPROVEMENT OF RESOLUTION BY USING A DIFFRACTION GRATING</u> , Proceedings of SPIE, 3568:185-196, 1999
SY	AS	S.W. Hell et al., <u>GROUND-STATE-DEPLETION FLUORESCENCE MICROSCOPY: A CONCEPT FOR BREAKING THE DIFFRACTION RESOLUTION LIMIT</u> , Applied Physics B 60, 495-497 (1995)
		R. Juškaitis et al., <u>EFFICIENT REAL-TIME CONFOCAL MICROSCOPY WITH WHITE LIGHT SOURCES</u> , Nature, Vol. 383:804-806, October 1996
SY	AT	Frederick Lanni et al., <u>EXCITATION FIELD SYNTHESIS AS A MEANS FOR OBTAINING ENHANCED AXIAL RESOLUTION IN FLUORESCENCE MICROSCOPES</u> , Bioimaging 1 (1993) 187-196
		Steffen Lindek et al., <u>TWO NEW HIGH-RESOLUTION CONFOCAL FLUORESCENCE MICROSCOPIES (4Pi, Theta) WITH ONE- AND TWO-PHOTON EXCITATION</u> , James B. Pawley, editor, Handbook of Biological Confocal Microscopy, Chapter 26:417-430, 1995

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S.Y.	AR	M.D. Duncan, <u>MOLECULAR DISCRIMINATION AND CONTRAST ENHANCEMENT USING A SCANNING COHERENT ANTI-STOKES RAMAN MICROSCOPE</u> , Optics Communications, Vol. 50, No. 5:307-312, July 1984
		Stefan Hell et al., <u>PROPERTIES OF A 4Pi CONFOCAL FLUORESCENCE MICROSCOPE</u> , Journal of the Optical Society of America, Vol. 9, No. 12:2159-2166, December 1992
	AS	
	AT	

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